

SprintMVP 250 | 300

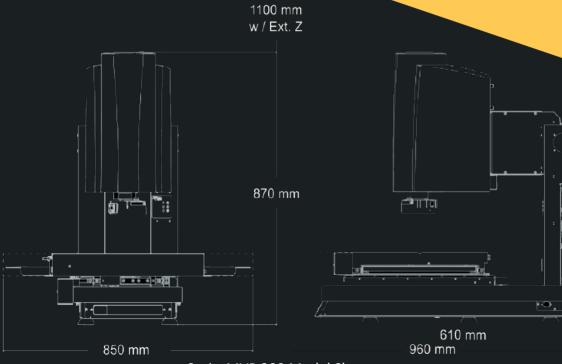


SprintMVP benchtop systems offer fully automatic measurement with high performance and affordability. Three benchtop SprintMVP models are available to suit your measurement needs.

- Granite base and column for stability with precision CNC X,Y and Z stages
- 3-axis joystick and CNC motion control
- Motorized zoom lens optics with high resolution digital color camera
- Optional 250mm extended Z axis



Automatic Benchtop Measuring Machines



SprintMVP 300 Model Shown

www.ogphommel.it



Technical data SprintMVP 250 | 300

	Standard Measuring Range (mm)					
odels		X	Υ			
	250	300	150			
Mo	300	300	300			

System Weight: Shipping Weight:

250 Model - 130 kg 300 Model - 180 kg 250 Model - 255 kg 300 Model - 300 kg

		Standard		Optional		
	250	300 x 150 x 150 mm		250 mm Extended Z Axis		
	300	300 x 300 x 150 mm		250 mm Extended Z Axis		
X, Y, Z Scale Resolution		0.5 μm		0.1 µm		
Stage Drive System		Precision, motorized compound XY stage and linear Z stage with 3-axis joystick control				
Max Recommended Stage Load		250 Models - 20 kg 300 Model - 25 kg				
Working Distance		62 mm (with standard VectorLight™)				
Imaging Optics		6.5:1, 10 position motorized zoom lens				
Lens Attachments			0.5X, 0.75X, 1.5X, 2.0X			
Field of View "Highest available magnification		Low Mag	High Mag*	Low Mag (0.5X)	High Mag (2.0X)*	
		7.3 mm x 5.5 mm	0.5 mm x 0.4 mm	14.6 mm x 11.0 mm	0.27 mm x 0.20 mm	
Metrology Camera		QVI Digital, Megapixel Color Metrology Camera				
Magnification on 24" LCD Monitor		24x to 370x on-screen digital/optical magnification standard with full feature Measure-X layout		12x to 740x on-screen digital/optical magnification with optional add-on lenses and dual monitor user interface		
Illumination		LED VectorLight™ SP programmable ring light with 6 rings and 7 sectors, LED backlight, LED square-on surface light		LED VectorLight™ SF programmable ring light with 6 rings and 8 sectors and LED square-on surface light (reduced working clearance)		
Sensor Options				Renishaw touch probe and change rack, QVI DRS™laser		
*Controller *Controller configuration subject to change without notice.		QVI standard system controller with networking and communication ports*		Single flat panel LCD monitor, or dual flat panel LCD monitors; keyboard, mouse		
Software		Measure-X		MeasureFit®, SmartReport®, CAD interface, SmartFeature® software for FDA compliant environments		
Miscellaneous Options		Manual or motorized rotary indexer, NIST traceable calibration artidust cover		, NIST traceable calibration artifact,		
Rated Enviro	onment	Temperature: 18-22 °C, stable to ±1 °C; Relative Humidity: 30-80%; Vibration: <0.001g below 15 Hz				
Power		100-120 VAC or 200-240 VAC, 50/60 Hz, 1 phase, 500W				
XY Area Acc	E ₂ : (2.5 + 6L/1000) μm					
Z Linear Accuracy		Е _i : (5.0 + 8L/1000) µm		E _; : (4.0 + 8L/1000) µm (with 2.0X lens attachment)		

Accuracy is evaluated with a QVI verification procedure where "L" is measured length in millimeters. Specifications apply within the rated environment. Standard optical specifications apply at the maximum optical magnification of the standard configuration. XY Accuracy applies with an evenly distributed load up to 5 kg in the standard measuring plane. The standard measuring plane is defined as a plane that is within 25 mm of the worktable surface. Depending on load distribution, accuracy at maximum payload may be less than standard.

